

Supporting Information for:

Imaging the $\text{TiO}_2(011)-(2\times 1)$ Surface using
Noncontact Atomic Force Microscopy and
Scanning Tunneling Microscopy

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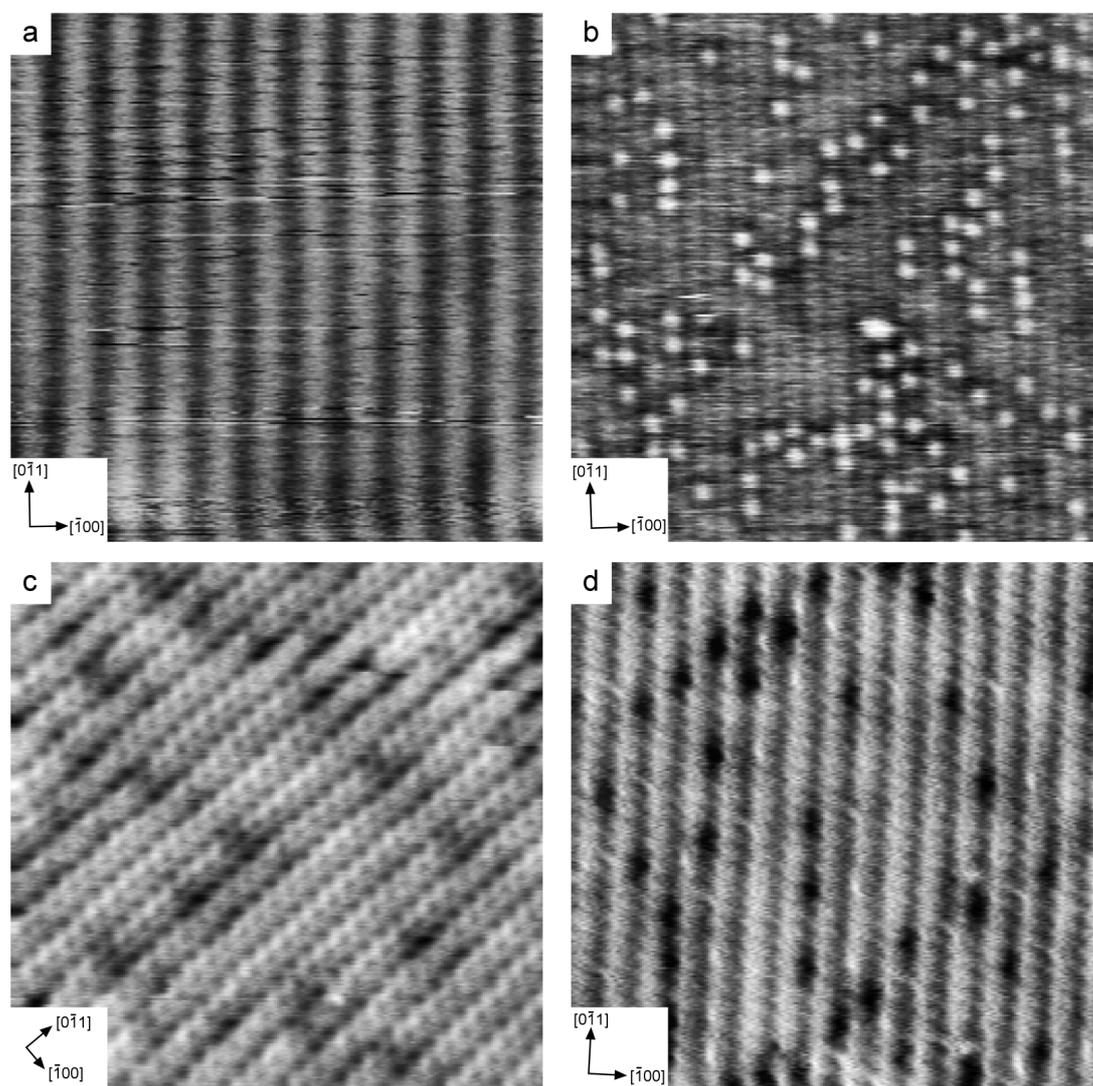


Figure S1 NC-AFM images of the TiO₂(011)-(2×1) surface with different contrasts. Image parameters are: **(a)** (100 Å)², $\Delta f = -11.9$ Hz, $V_{\text{CPD}} = 1.8$ V; **(b)** (200 Å)², $\Delta f = -60.5$ Hz, $V_{\text{CPD}} = 1.5$ V; **(c)** (125 Å)², $\Delta f = -14.4$ Hz, $V_{\text{CPD}} = 1.8$ V; and **(d)** (137.5 Å)², $\Delta f = -13.1$ Hz, $V_{\text{CPD}} = 1.8$ V.